Second IEEE International Workshop on
Automotive Reliability & Test

ART Workshop

Fort Worth Convention Center, TX, USA
November 2-3, 2017
held in conjunction with ITC 2017

http://ART.tttc-events.org

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Call for Submissions

The ART workshop focuses exclusively on test and reliability of automotive and mission-critical electronics, including design, manufacturing, burn-in, system-level integration and in-field test, diagnosis and repair solutions, as well as architectures and methods for reliable and safe operations under different environmental conditions. With increasing system complexity, security, stringent runtime requirements for functional safety, and cost constraints of a mass market, the reliable operation of electronics in safety-critical domains is still a major challenge. This second edition of the ART Workshop offers a forum to present and discuss these challenges and emerging solutions among researchers and practitioners alike.

ART will take place in conjunction with the IEEE International Test Conference (ITC) and is sponsored by the Test Technology Technical Council (TTTC) of IEEE Computer Society.

Topic Areas – You are invited to participate and submit your contributions to the ART Workshop. The workshop's areas of interest include (but are not limited to) the following topics:

- *Functional safety*
- *Robustness and security in automotive*
- *Multi-layer dependability evaluation*
- *Verification and validation of automotive systems*
- *Automotive standards and certification – ISO 26262*
- *Fault tolerance and self-checking circuits*
- *Dependability challenges of autonomous driving and e-mobility*

- *Transient events- effects and mitigation*
- *Aging effects on automotive electronics*
- *Power-up, power-down and periodic test*
- *System level test*
- *Built-In Self-Test (BIST and SBST) in automotive systems*
- *Reuse of test infrastructure*
- *Functional and structural test generation*
- *High quality volume test- minimizing DPPM*
- *Life cycle test cost minimization*

Submission Instructions – Submissions must be sent in as PDF file. The Workshop prefers Full Paper submissions (of up to six pages), but also allows Extended Abstract submissions (of at least two pages). Detailed submission instructions can be found at the Workshop's website: http://ART.tttc-events.org. All submissions will be evaluated for selection with respect to their suitability for the workshop, originality, technical soundness, and presented results. Selected submissions can be accepted for regular or poster presentation at the Workshop.

Publications – The workshop will make available to all participants an Electronic Workshop Digest, which includes all material that authors are willing to provide: abstract, paper, slides, poster, etc.

Key Dates
- Submission deadline   : **September 8, 2017**
- Notification of acceptance : **September 29, 2017**
- Camera-ready material   : **October 13, 2017**

Further Information

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Fort Worth Convention Center